NEC

MOS FIELD EFFECT TRANSISTOR

μPA1720

SWITCHING
N-CHANNEL POWER MOS FET
INDUSTRIAL USE

DESCRIPTION

The μPA1720 is N-Channel MOS Field Effect Transistor designed for DC / DC Converters and power management application of notebook computers.

FEATURES

- Low On-Resistance
  $R_{DS(on)1}$ = 25.0 mΩ MAX. (V_{GS} = 10 V, I_D = 4.0 A)
  $R_{DS(on)2}$ = 33.0 mΩ MAX. (V_{GS} = 4.5 V, I_D = 4.0 A)
  $R_{DS(on)3}$ = 38.0 mΩ MAX. (V_{GS} = 4.0 V, I_D = 4.0 A)
- Low C_{iss} : C_{iss} = 800 pF TYP.
- Built-in G-S Protection Diode
- Small and Surface Mount Package (Power SOP8)

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1720G	Power SOP8

ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C, All terminals are connected.)

Drain to Source Voltage (V_{GS} = 0)	V_{DSS}	30	V
Gate to Source Voltage (V_{DS} = 0)	V_{GSS}	±20	V
Drain Current (DC)	$I_{D(DC)}$	±8	A
Drain Current (Pulse) Note1	$I_{D(pulse)}$	±32	A
Total Power Dissipation (T_A = 25 °C) Note2	P_T	2.0	W
Single Avalanche Current Note3	I_{AS}	8.0	A
Single Avalanche Energy Note3	E_{AS}	6.4	mJ
Channel Temperature	T_{ch}	150	°C
Storage Temperature	T_{stg}	–55 to + 150	°C

Notes 1. PW ≤ 10 μs, Duty cycle ≤ 1 %

2. Mounted on ceramic substrate of 1200 mm^2 x 2.2 mm

3. Starting T_{ch} = 25 °C, R_G = 25 Ω, V_{GS} = 20 V → 0 V

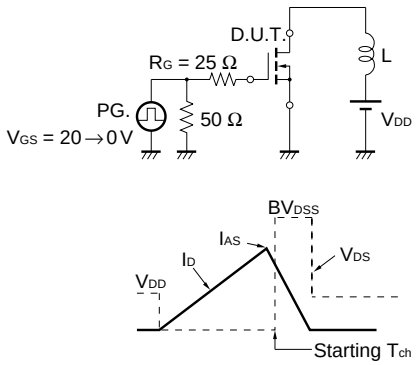
Document No. G13888EJ3V0DS00 (3rd edition)
Date Published April 2001 NS CP(K)
Printed in Japan

The mark ★ shows major revised points.

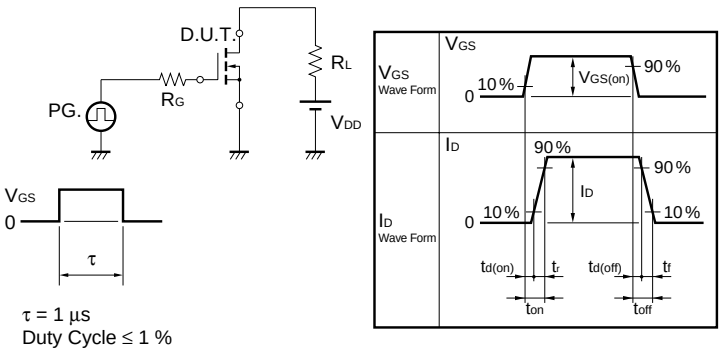
ELECTRICAL CHARACTERISTICS (T_A = 25 °C, All terminals are connected.)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	$R_{DS(on)1}$	V_{GS} = 10 V, I_D = 4.0 A		20.0	25.0	mΩ
	$R_{DS(on)2}$	V_{GS} = 4.5 V, I_D = 4.0 A		25.5	33.0	mΩ
	$R_{DS(on)3}$	V_{GS} = 4.0 V, I_D = 4.0 A		29.0	38.0	mΩ
Gate to Source Cut-off Voltage	$V_{GS(off)}$	V_{DS} = 10 V, I_D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	$\|y_{fs}\|$	V_{DS} = 10 V, I_D = 4.0 A	3.0	7.0		S
Drain Leakage Current	I_{DSS}	V_{DS} = 30 V, V_{GS} = 0 V			10	μA
Gate to Source Leakage Current	I_{GSS}	V_{GS} = ±16 V, V_{DS} = 0 V			±10	μA
Input Capacitance	C_{iss}	V_{DS} = 10 V		800		pF
Output Capacitance	C_{oss}	V_{GS} = 0 V		250		pF
Reverse Transfer Capacitance	C_{rss}	f = 1 MHz		96		pF
Turn-on Delay Time	$t_{d(on)}$	I_D = 4.0 A		20		ns
Rise Time	t_r	$V_{GS(on)}$ = 10 V		80		ns
Turn-off Delay Time	$t_{d(off)}$	V_{DD} = 15 V		40		ns
Fall Time	t_f	R_G = 10 Ω		40		ns
Total Gate Charge	Q_G	I_D = 8 A		14		nC
Gate to Source Charge	Q_{GS}	V_{DD} = 24 V		2.3		nC
Gate to Drain Charge	Q_{GD}	V_{GS} = 10 V		3.6		nC
Body Diode Forward Voltage	$V_{F(S-D)}$	I_F = 8 A, V_{GS} = 0 V		0.86		V
Reverse Recovery Time	t_{rr}	I_F = 8 A, V_{GS} = 0 V		30		ns
Reverse Recovery Charge	Q_{rr}	di/dt = 100 A/ μs		40		nC

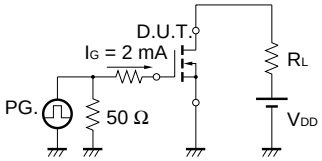
TEST CIRCUIT 1 AVALANCHE CAPABILITY



TEST CIRCUIT 2 SWITCHING TIME

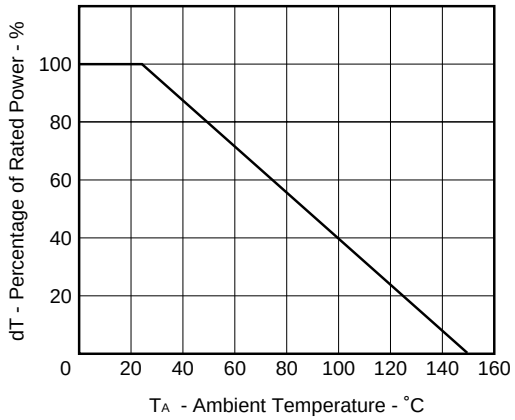


TEST CIRCUIT 3 GATE CHARGE

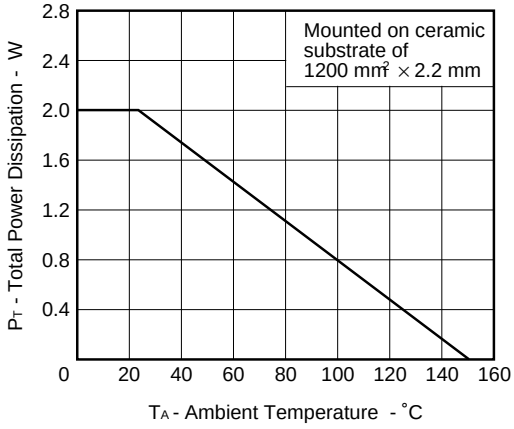


TYPICAL CHARACTERISTICS (T_A = 25 °C)

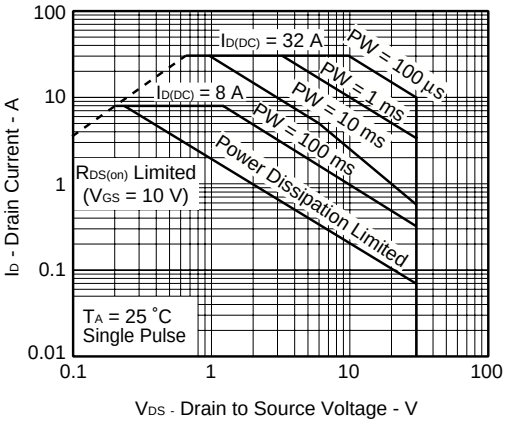
DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA



TOTAL POWER DISSIPATION vs. AMBIENT TEMPERATURE

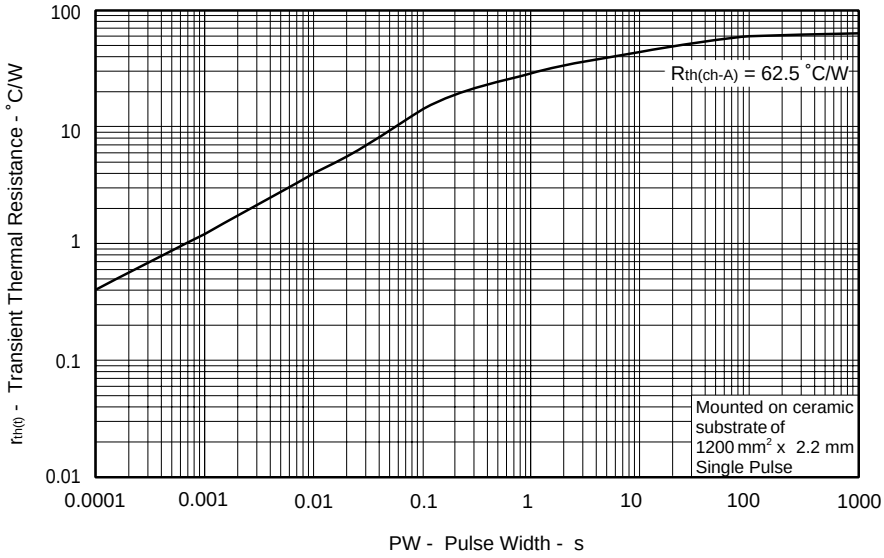


★ FORWARD BIAS SAFE OPERATING AREA

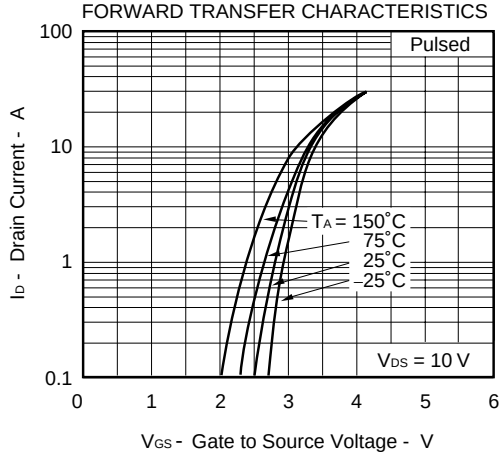


Remark Mounted on ceramic substrate of 1200 mm² × 2.2 mm

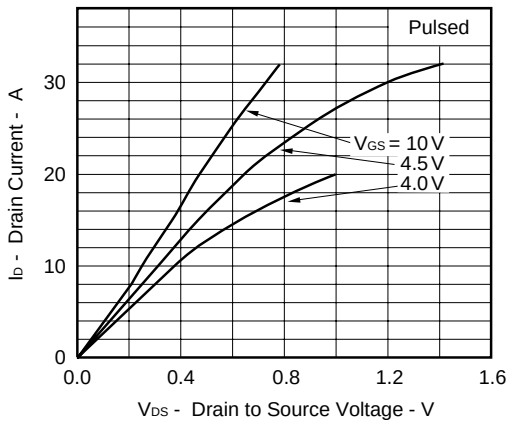
★ TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



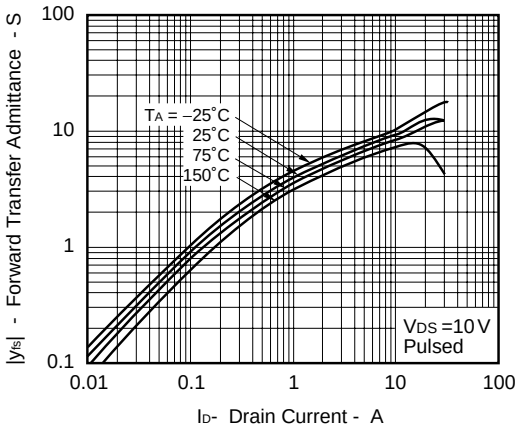
FORWARD TRANSFER CHARACTERISTICS



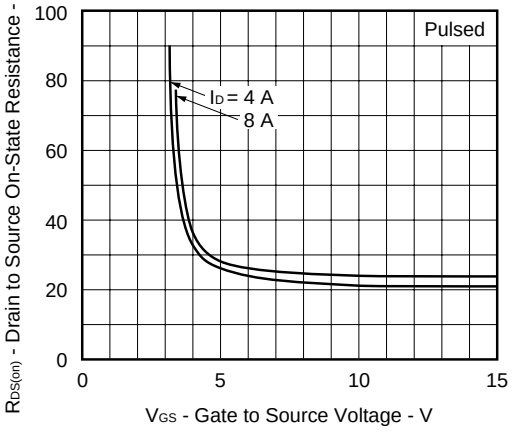
DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE



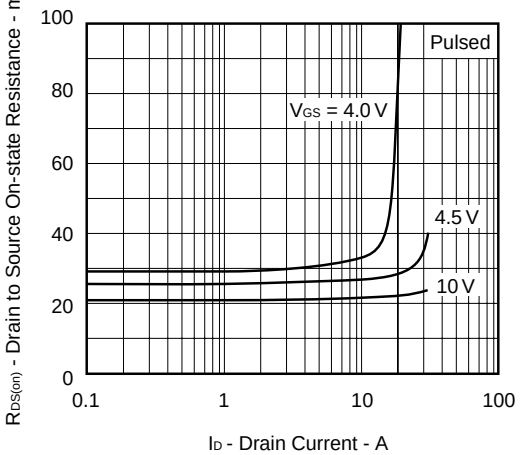
FORWARD TRANSFER ADMITTANCE vs.
DRAIN CURRENT



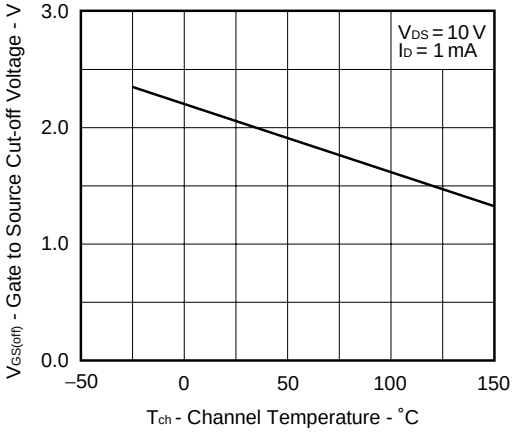
DRAIN TO SOURCE ON-STATE RESISTANCE vs.
GATE TO SOURCE VOLTAGE



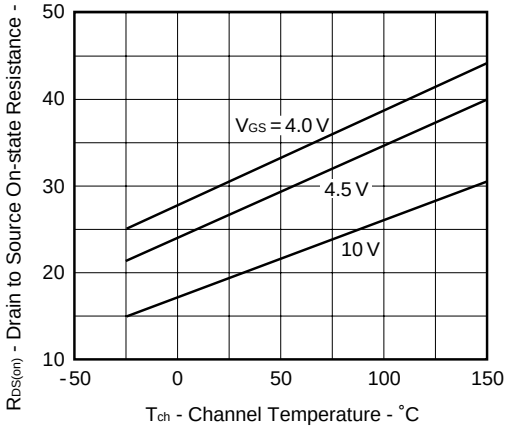
DRAIN TO SOURCE ON-STATE
RESISTANCE vs. DRAIN CURRENT



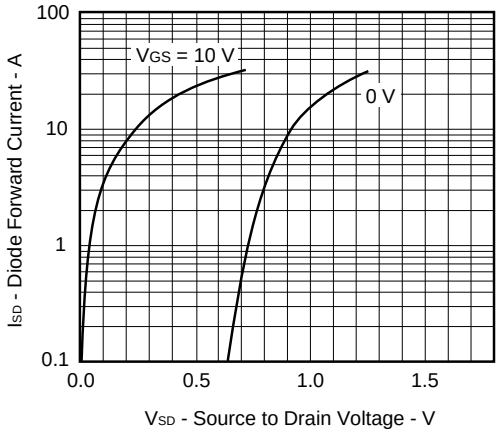
GATE TO SOURCE CUT-OFF VOLTAGE vs.
CHANNEL TEMPERATURE



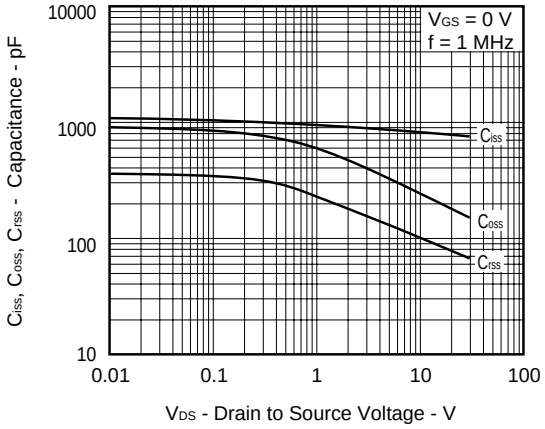
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



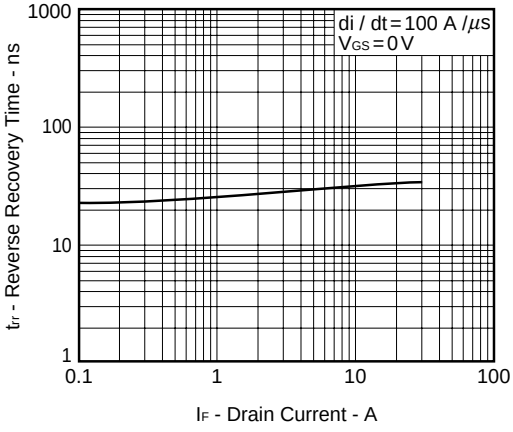
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



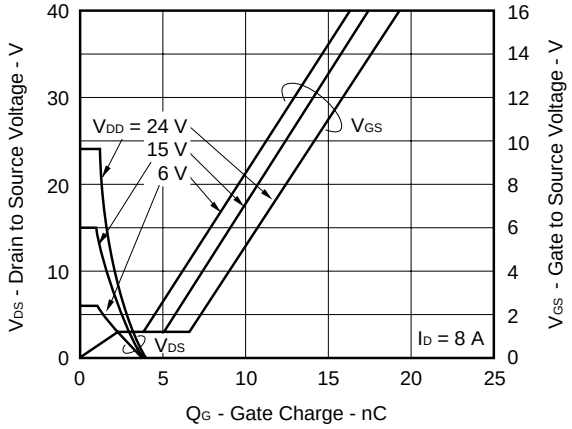
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



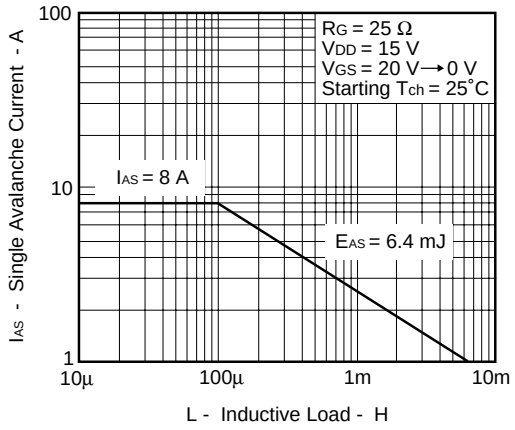
REVERSE RECOVERY TIME vs. DRAIN CURRENT



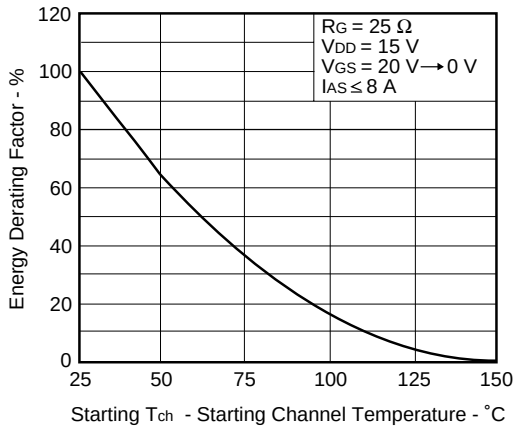
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SINGLE AVALANCHE CURRENT vs.
INDUCTIVE LOAD

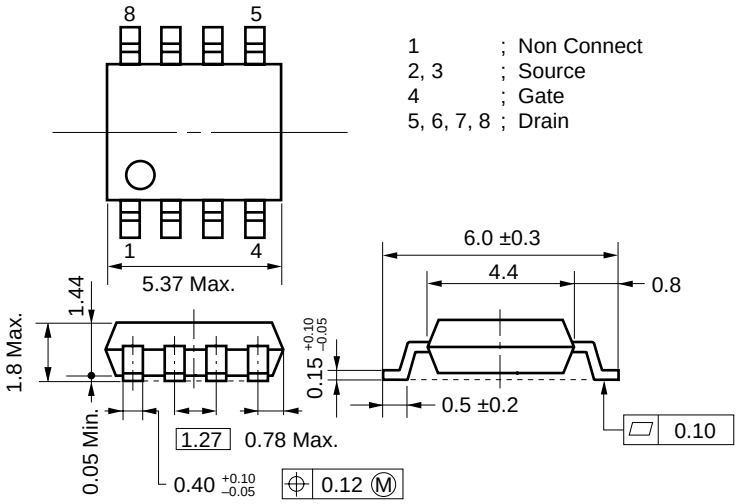


SINGLE AVALANCHE ENERGY
DERATING FACTOR

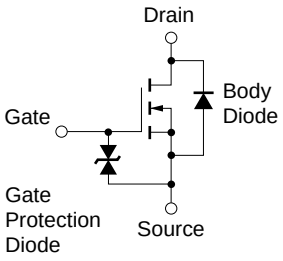


PACKAGE DRAWING (Unit : mm)

Power SOP8



EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage Exceeding the rated voltage may be applied to this device.

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